

PUTs

Planar, TO-18, Hermetic

2N6119-2N6120

FEATURES

- Hermetically Sealed TO-18 Metal Can
- Programmable Eta, R_{BB} , I_p and I_v
- Maximum Peak Point Current: 150mA
- Minimum Valley Current to 1.5mA
- Nario-Amp Leakage
- Passivated Planar Construction for Maximum Reliability and Parameter Uniformity

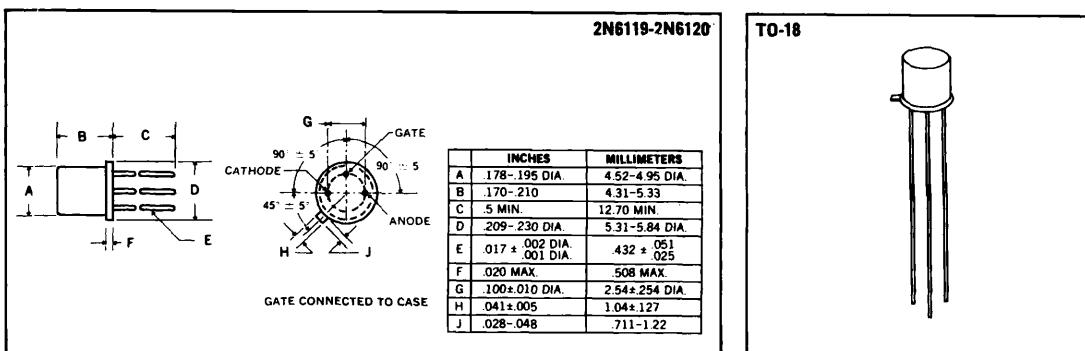
DESCRIPTION

Functionally equivalent to standard unijunction transistors, Unitrode's Programmable Unijunction Transistors offer the distinct advantage of versatile programming. External resistors can be added to meet the designer's needs in programming Eta, R_{BB} , I_p and I_v functions. This series also features a hermetically sealed TO-18 package for optimum reliability in all environmental conditions. Applications include pulse and timing circuits, SCR trigger circuits, relaxation oscillators and sensing circuits. For additional information see Unitrode Application Note U-66.

ABSOLUTE MAXIMUM RATINGS

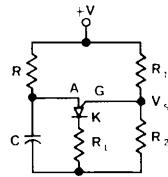
| | |
|---|-----------------|
| Anode-to-Cathode Voltage, V_{AK} | $\pm 40V$ |
| Gate-to-Cathode Forward Voltage, V_{GK} | 40V |
| Gate-to-Anode Reverse Voltage, V_{GAR} | 40V |
| Gate-to-Cathode Reverse Voltage, V_{GCR} | -5V |
| Peak Recurrent Forward Current 10μs, 1% Duty Cycle | 8A |
| 100μs, 1% Duty Cycle | 5A |
| Power Dissipation 25°C Ambient | 400mW |
| Derating Factor | 3.2mW/°C |
| Storage Temperature | -55°C to +125°C |
| Operating Temperature Range | -55°C to +125°C |

MECHANICAL SPECIFICATIONS

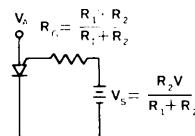


ELECTRICAL SPECIFICATIONS (at 25°C unless noted)

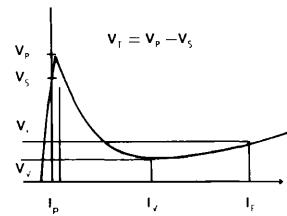
| Test | Symbol | Fig. | 2N6119 | | 2N6120 | | Units | Test Conditions |
|---------------------------|-----------|------|----------------|--------------|----------------|--------------|----------------------------|--|
| | | | Min. | Max. | Min. | Max. | | |
| Peak Current | I_p | 1 | — | 5 2 | — | 1.0 0.15 | μA μA | $R_G = 10k$, $V_S = 10V$ $R_G = 1 \text{ Meg.}$ |
| Valley Current | I_v | 1 | 70 — 1.5 | — 50 — | 25 — 1.0 | — 25 — | μA μA mA | $R_G = 10k$, $V_S = 10V$ $R_G = 1 \text{ Meg.}$ $R_G = 200\Omega$ |
| Offset Voltage | V_T | 1 | 0.2 0.2 | 0.6 1.6 | 0.2 0.2 | 0.6 0.6 | V V | $R_G = 10k$, $V_S = 10V$ $R_G = 1 \text{ Meg.}$ |
| Gate-to-Anode Leakage | I_{GAO} | 2 | — | 10 100 | — | 10 100 | nA nA | $T = 25^\circ C$, $V_S = 40V$ $T = 75^\circ C$ |
| Gate-to-Cathode Leakage | I_{GKS} | 3 | — | 100 | — | 100 | nA | $V_S = 40V$ |
| Forward Voltage | V_F | 4 | — | 1.0 | — | 1.0 | V | $I_F = 50mA$ |
| Pulse Output Voltage | V_o | 5 | 9 | — | 9 | — | V | |
| Pulse Output Rate of Rise | t_r | 5 | — | 80 | — | 80 | ns | |



a) Typical Circuit



b) Equivalent Test Circuit



c) Characteristic Curve

Figure 1

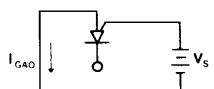


Figure 2

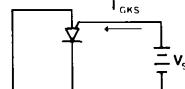


Figure 3

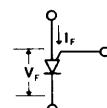


Figure 4

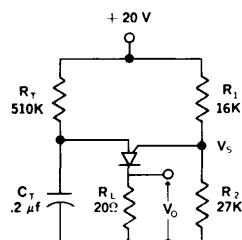


Figure 5

